




PCN Number:	20161027001	PCN Date:	Nov. 2, 2016				
Title:	Transfer of select C10 devices from ANAM-1 to DMOS5 Wafer Fab site						
Customer Contact:	PCN Manager	Dept:	Quality Services				
Proposed 1st Ship Date:	Feb. 2, 2017	Estimated Sample Availability:	Date provided at sample request.				
Change Type:							
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process				
<input type="checkbox"/>	Design	<input type="checkbox"/>	Assembly Materials				
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Electrical Specification				
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Mechanical Specification				
<input checked="" type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Packing/Shipping/Labeling				
		<input type="checkbox"/>	Test Process				
		<input type="checkbox"/>	Wafer Bump Material				
		<input type="checkbox"/>	Wafer Bump Process				
		<input type="checkbox"/>	Wafer Fab Materials				
		<input type="checkbox"/>	Wafer Fab Process				
		<input type="checkbox"/>	Part number change				
PCN Details							
Description of Change:							
<p>This change notification is to announce the transfer of select devices from ANAM-1 to the DMOS5 Wafer Fab site. Fab support from ANAM-1 is being discontinued for the products listed in the product affected section of this document. Production at ANAM-1 will stop on February 28, 2017. Customers are advised to place their orders immediately to ensure fulfillment. Any orders placed after this date will be supported with DMOS5 material.</p>							
Current (Discontinued)		New (Transfer to Location)					
Current Fab Site	Process	Wafer Diameter	New Fab Site				
ANAM-1	C10	200mm	DMOS5				
			Process				
			C10				
			Wafer Diameter				
			200mm				
Reason for Change:							
Continuity of Supply							
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):							
None							
Changes to product identification resulting from this PCN:							
Current:							
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City				
ANAM-1	ANM	KOR	Bucheon-si				
New:							
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City				
DP1DM5	DM5	USA	Dallas				
Sample product shipping label (not actual product label)							
 <p>TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 20:</p> <table border="1"> <tr> <td>MSL 2 / 260C / 1 YEAR</td> <td>SEAL DT</td> </tr> <tr> <td>MSL 1 / 235C / UNLIM</td> <td>03/29/04</td> </tr> </table> <p>OPT: ITEM: 39 LBL: 5A (L)T0:1750</p>	MSL 2 / 260C / 1 YEAR	SEAL DT	MSL 1 / 235C / UNLIM	03/29/04			<p>(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483SI2 (P) (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CCO: USA (22L) ASU: MLA (23L) ACU: MYS</p>
MSL 2 / 260C / 1 YEAR	SEAL DT						
MSL 1 / 235C / UNLIM	03/29/04						
Product Affected:							
CDCV304PW	CDCV304PWG4	CDCV304PWR	CDCV304PWRG4				

Qualification Report

CDCV304: Qualification of alternative FAB (DMOS5)

Approve Date 04-Dec-2015

Product Attributes

Attributes	Qual Device: CDCV304	QBS Product Reference: CDCV304	QBS Process Reference: SN74AVC16T245DGGGR	QBS Package Reference: CDCVF2505PW	QBS Package Reference: LMV324IPWR	QBS Package Reference: RC4558PWR	QBS Package Reference: SN0508073PW
Wafer Fab Supplier	DMOS5	DMOS5	CFAB	ANAM-I	FFAB	SFAB	MLA
Wafer Process	33C10	33C10	33C10	33C10	BCB	JI-SLM	LBC4X
Assembly Site	MLA	MLA	MLA	MLA	ASE SHANGHAI	MLA (TIM)	MLA
Package Family	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP

- QBS: Qual By Similarity

- Qual Device CDCV304 is qualified at LEVEL1-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: CDCV304	QBS Product Reference: CDCV304	QBS Process Reference: SN74AVC16T245DGGGR	QBS Package Reference: CDCVF2505PW	QBS Package Reference: LMV324IPWR	QBS Package Reference: RC4558PWR	QBS Package Reference: SN0508073PW
AC	Autoclave 121C	96 Hours	-	1/77/0	3/231/0	3/231/0	-	1/77/0	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	-	Pass	Pass	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	3/231/0	-	2/154/0	1/77/0	-
HAST	Biased HAST, 130C/85%RH	192 Hours	-	-	-	-	2/154/0	-	-
HBM	ESD - HBM	2500 V	1/3/0	1/3/0	3/9/0	-	-	-	-
CDM	ESD - CDM	1000 V	1/3/0	1/3/0	3/9/0	-	-	-	-
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	-	-	-	-	-	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/231/0	3/231/0	1/77/0	-	3/231/0
HTOL	High Temp Operating Life, 150C	300 Hours	-	-	3/231/0	-	-	-	-
LU	Latch-up	(per JESD78)	1/6/0	-	3/18/0	-	-	-	-
TC	Temperature Cycle, -55/125C	700 Cycles	-	-	-	-	-	-	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	3/231/0	3/231/0	-	1/77/0	3/231/0
TS	Thermal Shock, -65/150C	500 Cycles	-	-	-	3/231/0	-	-	3/231/0
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	-	-	1/77/0	-	-
WBP	Bond Strength	Wires	-	-	3/228/0	-	2/154/0	1/76/0	-
MQ	Manufacturability	(per mfg. Site specification)	Pass	Pass	-	-	-	-	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com